

**Notice of References Cited**Application/Control No.  
09/934,723Applicant(s)/Patent Under  
Reexamination  
EBINGER, MARTINExaminer  
Wenpeng ChenArt Unit  
2624

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,590,578	05-1986	Barto et al.	700/254
	B	US-5,444,836	08-1995	Hollingsworth et al.	345/634
	C	US-5,561,606	10-1996	Ota et al.	716/19
	D	US-5,917,932	06-1999	Hartley, John George	382/144
	E	US-6,064,759	05-2000	Buckley et al.	382/154
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Automated Precision Measurement of Surface Profile in CAD-Directed Inspection," Meng, Chia-Hsiang, et al., IEEE transactions on Robotics and Automation, vol. 8, no. 2, April 1992, pages 268-278.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.